

<b>Notice of References Cited</b>	Application/Control No. 10/625,733	Applicant(s)/Patent Under Reexamination NITTA ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0227051	12-2003	Kurosaki et al.	257/330
	B	US-6,610,570	08-2003	Chen, Chin-Yang	438/257
	C	US-6,614,089	09-2003	Nakamura et al.	257/492
	D	US-2003/0132450	07-2003	Minato et al.	257/110
	E	US-6,642,120	11-2003	Terashima, Tomohide	438/309
	F	US-6,650,001	11-2003	Yamaguchi et al.	257/557
	G	US-2003/0219945	11-2003	Lee, Sun-Hak	438/257
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 6-318561	11-1994	Japan	Hayashi	
	O	JP 6-97438	04-1994	Japan	Morikawa et al	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.